

ECB-920A

PCB Rev. A0.3_0_0

Temperature/Humidity Test Report

Report NO:

| | |
|----------------|---|
| Summary | <p><input checked="" type="checkbox"/> Pass <input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input type="checkbox"/> Pass with Deviation</p> |
|----------------|---|

Issue date

2013-09-09

Approval

Benson Lee

Test Engineer

Ronald Lin

Test item list

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Testing Result

| Num | Test item list | Result | Remark |
|-----|--------------------------------------|--------|--------|
| 1 | Temp./humidity power on/off test | Pass | N/A |
| 2 | Temperature variation operation test | Pass | N/A |
| 3 | Cold start and hot start test | Pass | N/A |

Configuration of EUT

Test Product: ECB-920A A0.3 + COM-QM87 A0.2

Sample Configuration & Quantity Under Test:

1. **CPU:** Intel Haswell i7-4700EQ CPU @2.4GHz
2. **Chipset:** PCH/Lynx Point
3. **VGA:** Intel HD Graphics 4600
4. **Memory:** Transcend 4GB DDR3 1333 SODIMM / TS512MSK64V3N
5. **BIOS Reversion:** COM-QM87 R1.1 (CM87AM11) (08/01/2013)
6. **SATA HDD:** INTEL SATA SSD SSDSC2BW180A4
7. Test Software: Windows 7 32-bit/ Run PassMark BurnInTest Pro v7.0
8. Power Supply: HG2-6300P
9. CPU Cooler



Temp./humidity power on/off test

Test Date: 2013-08-29~08-30

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-30 Testing procedures
Test Db: Damp Heat Test

Test Equipment:

Programmable Temperature & Humidity Chamber

TERCHY. TECH. CORP.

Model: MHK-225NK

Date of Calibration: 2013/03/18

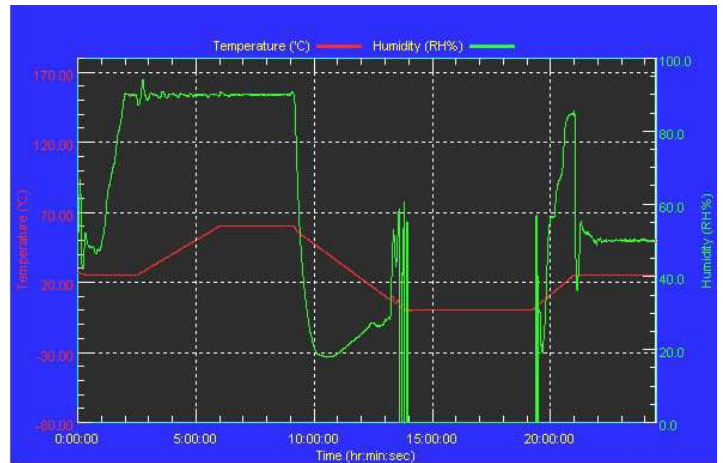
Serial Number: 1000122

Temperature & Humidity Power On/Off Test:

Testing Specification:

| Step | Temperature (°C) | Humidity (%RH) | Duration (HH:MM) |
|------|------------------|----------------|------------------|
| 1 | 25 | 50 | 00:30 |
| 2 | 25 | 50 | 00:30 |
| 3 | 25 | 90 | 01:00 |
| 4 | 25 | 90 | 00:30 |
| 5 | 60 | 90 | 03:30 |
| 6 | 60 | 90 | 03:00 |
| 7 | 0 | 0 | 04:50 |
| 8 | 0 | 0 | 05:23 |
| 9 | 25 | 50 | 01:47 |
| 10 | 25 | 50 | 03:00 |

Test Curve:



Test Result:

No problem was found during the temperature & humidity power on/off test.

| Test Method | Actual | Successful | Failure rate |
|--|--------------------|--------------------|--------------|
| Power On/Off | 2100/ times | 2100/ times | 0 % |
| Note: Failure rate need to under 0.2%. | | | |

Temperature variation operation test

Test Date: 2013-09-03~09-04

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

TERCHY. TECH. CORP.

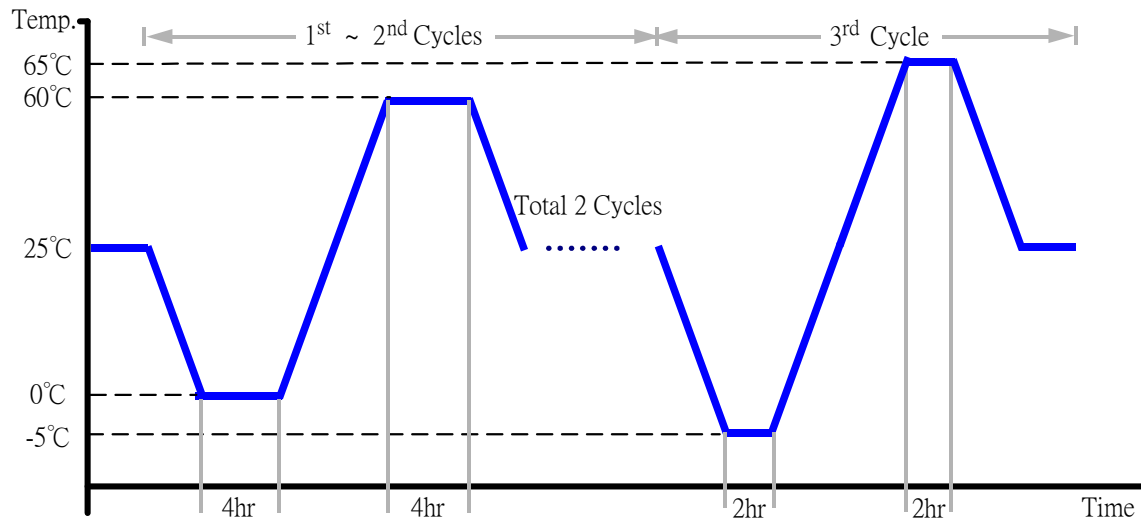
Model: MHK-225NK

Date of Calibration: 2013/03/18

Serial Number: 1000122

Temperature & Humidity Cycle Test:

1. Test Low Temperature: **0°C** (1st~2nd cycles)
-5°C (3rd cycle)
2. Test High Temperature: **60°C** (1st~2nd cycles)
65°C (3rd cycle)
3. Test dwell time: **4Hrs** (1st~2nd cycles)
2Hrs (3rd cycle)
4. Temperature slope: **2°C/min**
5. Test cycle: **3 cycles**
6. Test Environment Curve:



Test Result:

No problem was found during the temperature variation operation test.

Cold start and hot start test

Test Date: 2013-09-05~09-06

Test Site: AAEON Taichung Internal Lab

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber

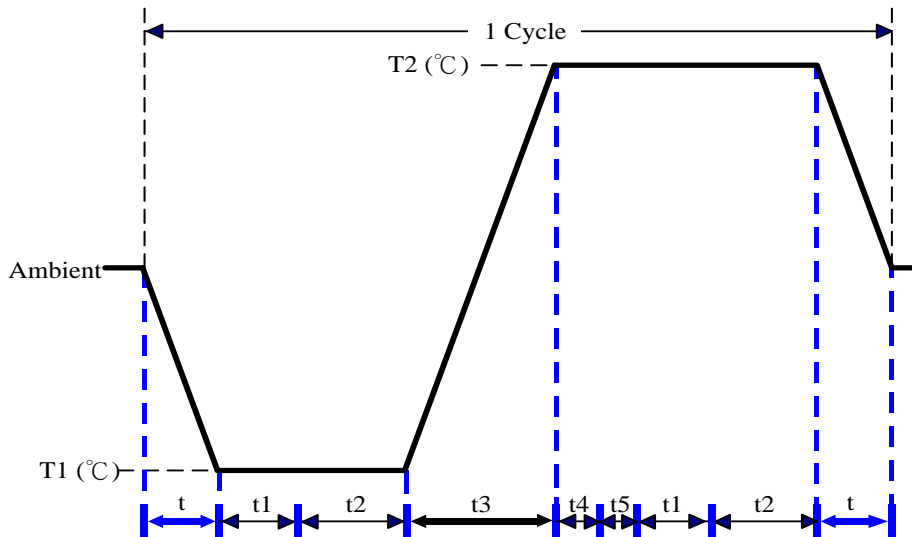
TERCHY. TECH. CORP.

Model: MHK-225NK

Date of Calibration: 2013/03/18

Serial Number: 1000122

Test Condition:



| Parameters | Description |
|------------|-------------|
| T1 | -5°C |
| T2 | 65°C |
| t1 | 1 hr |
| t2 | 2 hrs |
| t4, t5 | 30 mins |
| t, t3 | 2°C/min |
| n (Cycle) | 1 |

t, t3: Temperature Slope

t, t1: Power Off

t2: Power On/Off test 10 times (On 2 mins / Off 5 mins)

t5: Windows soft restart test 2 times

Test software: Windows 7 Ultimate x32 Edition

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.